

## Product Overview

NSE11409-Q1 is a 90mΩ low-side switch with 48V clamp voltage for automotive applications. It's designed for driving resistive or inductive loads with one side connected to the battery. Internal 48V clamp circuit protects device from surge energy when fast demagnetization at turn-off.

With internal output current limitation, the device is protected in overload condition. Built-in thermal shutdown protects the chip from over-temperature and short-circuit. A thermal swing mechanism is built to limit dissipated power to decelerate power accumulation. Thermal shutdown, with automatic restart, allows the devices to recover normal operation as soon as a fault condition disappears.

An internal diagnostic function is built to indicate any faults when thermal shutdown and open-drain conditions through an open-drain status output pin. This device operates in ambient temperatures from -40°C to 125°C.

## Key Features

- AEC-Q100 qualified
- Drain current limitation: 8.5A
- 48V overvoltage clamp
- Thermal shutdown protection
- Thermal swing protection
- Fault diagnostic block
  - Thermal shutdown diagnosis
  - Open-drain diagnosis
- Very low standby current
- Very low electromagnetic susceptibility
- ESD protection
- RoHS-compliant package

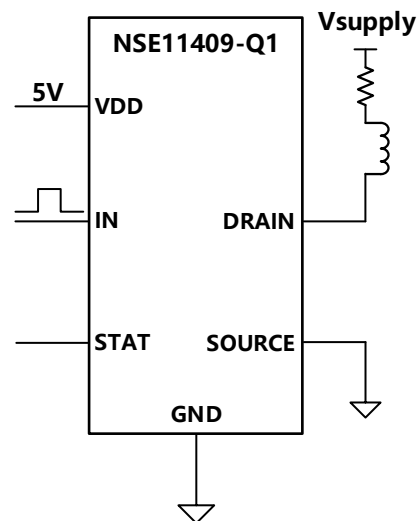
## Applications

- Automotive Relays
- Solenoids
- Valves
- Lighting

## Device Information

Part Number	Package	Body Size
NSE11409-QSPR	SOP8	4.9mm x 3.9mm
NSE11409-QSTBR	SOT223	6.48mm x 3.38mm

## Typical Application



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### 1. Pin Configuration and Functions

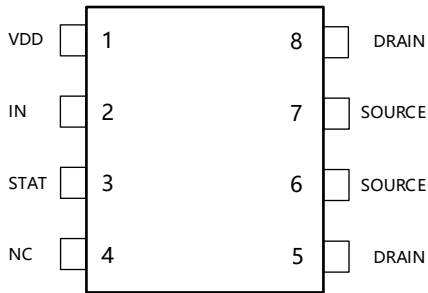


Figure 1-1 Pin Configuration

Table 1 SOP8 Pin Configuration and Description

PIN NO.	SYMBOL	FUNCTION
1	VDD	Power supply pin.
2	IN	CMOS compatible, voltage controlled input pin.
3	STAT	Open drain digital diagnostic pin.
4	NC	Not connect.
5, 8	DRAIN	PowerMOS drain.
6, 7	SOURCE	PowerMOS source.

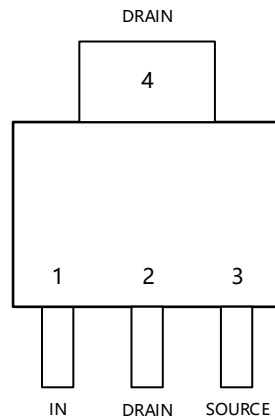


Figure 1-2 Pin Configuration

Table 2 SOT223 Pin Configuration and Description

PIN NO.	SYMBOL	FUNCTION
1	IN	CMOS compatible, voltage controlled input pin.
2, 4	DRAIN	PowerMOS drain.
3	SOURCE	PowerMOS source.

## 2. Block diagram

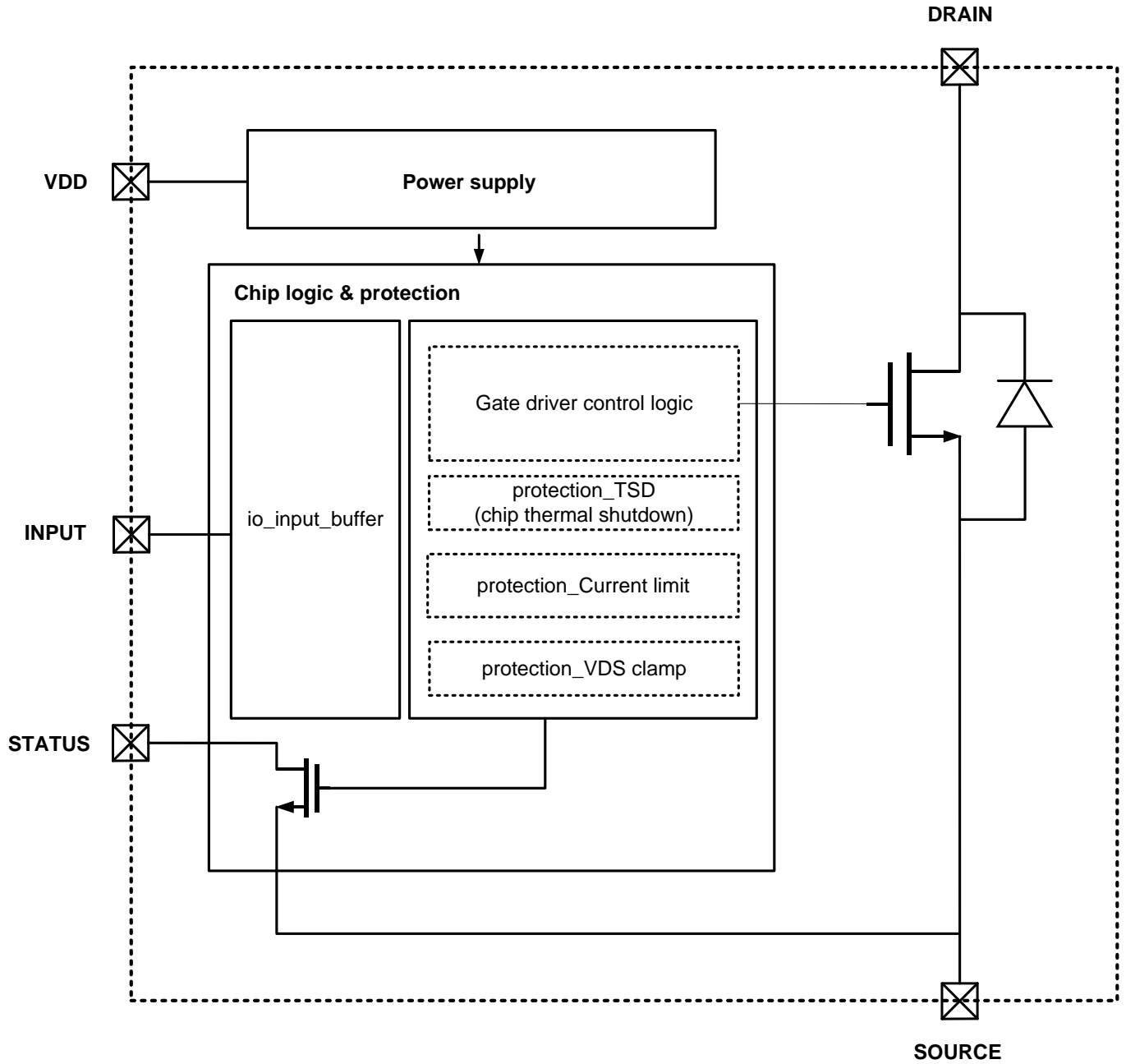


Figure 2-1 Block diagram

### 3. Absolute Maximum Ratings

Parameters	Symbol	Min	Typ	Max	Unit
Drain-to-Source Voltage	$V_{DS}$			Internally clamped	V
DC Drain Current	$I_D$			Thermal limited	A
Reverse DC drain current	$-I_D$			12.5	A
VDD Pin Current	$I_{VDD}$	-1		10	mA
INPUT Pin Current	$I_{IN}$	-1		10	mA
STATUS Pin Current	$I_{STAT}$	-1		10	mA
Junction Temperature	$T_J$	-40		150	°C
Storage Temperature	$T_{stg}$	-55		150	°C
Electrostatic discharge, Human-body model	HBM	-3000		3000	V
Electrostatic discharge, Charged-device model	CDM	-2000		2000	V
Single pulse avalanche energy ( $L=90\text{mH}$ , $I_{DS}=1.5\text{A}$ , $VCC=13.5\text{V}$ )	Eas		73 <sup>(1)</sup>		mJ

Notes:

- 1). Not subject to production test, bench evaluation

### 4. Thermal Information

Parameters	Symbol	SO-8	SOT223	Unit
IC Junction-to-ambient Thermal Resistance	$\theta_{JA}$	94.5 <sup>(1)</sup>	73 <sup>(1)</sup>	°C/W
Junction-to-case (top) thermal resistance	$\theta_{JC(TOP)}$	44.5	41.5	°C/W
Junction-to-board thermal resistance	$\theta_{JB}$	47	18.5	°C/W
Junction-to-case (bottom) thermal resistance	$\theta_{JC(bot)}$	-	18	°C/W

Notes:

- 1). Four layers 2s2p PCB JEDEC JESD 51-7

### 5. Specifications

#### 5.1. Electrical Characteristics

( $VDD = VIN = 4.5\text{ V to }5.5\text{ V}$ ,  $T_J = -40^\circ\text{C to }150^\circ\text{C}$ . Unless otherwise noted.)

Parameters	Symbol	Min	Typ	Max	Unit	Comments
<b>Power MOSFET</b>						
ON-state resistance	$R_{ON}$		90	180	mΩ	$I_D = 1.6\text{ A}$ ; $V_{DD} = V_{IN} = 5\text{ V}$
Drain-source clamp voltage	$V_{CLAMP}$	46	48	56	V	$V_{IN} = 0\text{ V}$ ; $I_D = 1.6\text{ A}$
Drain-source clamp threshold voltage	$V_{CLTH}$	40			V	$V_{IN} = 0\text{ V}$ ; $I_D = 2\text{ mA}$
OFF-state output current	$I_{DSS}$	0		3	μA	$V_{IN} = 0\text{ V}$ ; $V_{DS} = 13\text{ V}$ ; $T_j = 25^\circ\text{C}$
		0		5	μA	$V_{IN} = 0\text{ V}$ ; $V_{DS} = 13\text{ V}$ ; $T_j = 125^\circ\text{C}$
Bode diode forward voltage	$V_{BD}$		0.8		V	$I_D = 1.6\text{ A}$ ; $V_{IN} = 0\text{ V}$
<b>VDD ( NSE11409-QSTBR supplied by pin IN )</b>						
Operating supply voltage	$V_S$	3.5	5	5.5	V	
Operating supply current	$I_S$		10	25	μA	OFF-state; $T_j = 25^\circ\text{C}$ ; $V_{IN} = V_{DS} = 0\text{ V}$ ;
			25	65		ON-state; $V_{IN} = 5\text{ V}$ ; $V_{DS} = 0\text{ V}$
Supply clamp voltage	$V_{SCL}$	5.5		8	V	$I_{SCL} = 1\text{ mA}$
			-0.7			$I_{SCL} = -1\text{ mA}$
<b>Logic Input ( NSE11409-QSPR only )</b>						
Low-level input voltage	$V_{IL}$			0.9	V	
Low-level input current	$I_{IL}$	1			μA	$V_{IN} = 0.9\text{ V}$
High-level input voltage	$V_{IH}$	2.1			V	
High-level input current	$I_{IH}$			10	μA	$V_{IN} = 2.1\text{ V}$
Input hysteresis voltage	$V_{I(hyst)}$	0.13			V	
Input clamp voltage	$V_{ICL}$	5.5		8		$I_{IN} = 1\text{ mA}$
			-0.7			$I_{IN} = -1\text{ mA}$
<b>Status indicator ( NSE11409-QSPR only )</b>						
Status low output voltage	$V_{STAT}$		0.5		V	$I_{STAT} = 1\text{ mA}$
Status leakage current	$I_{LSTAT}$			10	μA	$V_{STAT} = 5\text{ V}$
Status pin input capacitance	$C_{STAT}$			100	pF	$V_{STAT} = 5\text{ V}$
Status clamp voltage	$V_{STCT}$	5.5		8	V	$I_{STAT} = 1\text{ mA}$

Parameters	Symbol	Min	Typ	Max	Unit	Comments
			-0.7			I <sub>STAT</sub> = - 1 mA
<b>Open load detection ( NSE11409-QSPR only )</b>						
Open load OFF-state voltage detection threshold	V <sub>O1</sub>	1.1	1.2	1.3	V	V <sub>IN</sub> = 0 V
Delay between INPUT falling edge and STATUS falling edge in open load condition	t <sub>d(STAT)</sub>		225		μs	I <sub>OUT</sub> = 0 A
<b>Switching characteristics (V<sub>supply</sub> = V<sub>IN</sub> = 3.5V to 5.5 V, See Figure 5-1 for Switching timing characteristics)</b>						
Turn-on delay time	t <sub>d(ON)</sub>		8		μs	R <sub>L</sub> = 8.2 Ω; V <sub>CC</sub> = 13 V
Turn-off delay time	t <sub>d(OFF)</sub>		18		μs	R <sub>L</sub> = 8.2 Ω; V <sub>CC</sub> = 13 V
Rise time	t <sub>r</sub>		10		μs	R <sub>L</sub> = 8.2 Ω; V <sub>CC</sub> = 13 V
Fall time	t <sub>f</sub>		10		μs	R <sub>L</sub> = 8.2 Ω; V <sub>CC</sub> = 13 V
Switching energy losses at turn-on	W <sub>ON</sub>		57		μJ	R <sub>L</sub> = 8.2 Ω; V <sub>CC</sub> = 13 V
Switching energy losses at turn-off	W <sub>OFF</sub>		55		μJ	R <sub>L</sub> = 8.2 Ω; V <sub>CC</sub> = 13 V
<b>Protection and diagnostics</b>						
DC short-circuit current	I <sub>limH</sub>	5.5	8.5	11.5	A	V <sub>DS</sub> = 13 V; V <sub>S</sub> = V <sub>IN</sub> = 5V
Shutdown temperature	TTSD	150	175	200	°C	
Reset temperature	TR	T <sub>RS</sub> + 1	T <sub>RS</sub> + 5		°C	
Thermal reset of STATUS	TRS	135			°C	
Thermal hysteresis (TTSD- TR)	THYST		7		°C	
Dynamic temperature	ΔT <sub>j</sub>		40		K	T <sub>j</sub> = -40°C; V <sub>CC</sub> = 13V
Dynamic temperature hysteresis	ΔT <sub>j</sub> (HYS)		15		K	

## 5.2. Typical Performance Characteristics

### 5.2.1. True table

Conditions	Input	Drain	Status
Normal operation	L	H	H
	H	L	H
Current limitation	L	H	H
	H	X	H
Over-temperature limitation	L	H	H

Conditions	Input	Drain	Status
	H	H	L
VDD under-voltage	L	H	X
	H	H	X
Open-drain detection	L	L	L
	H	L	H

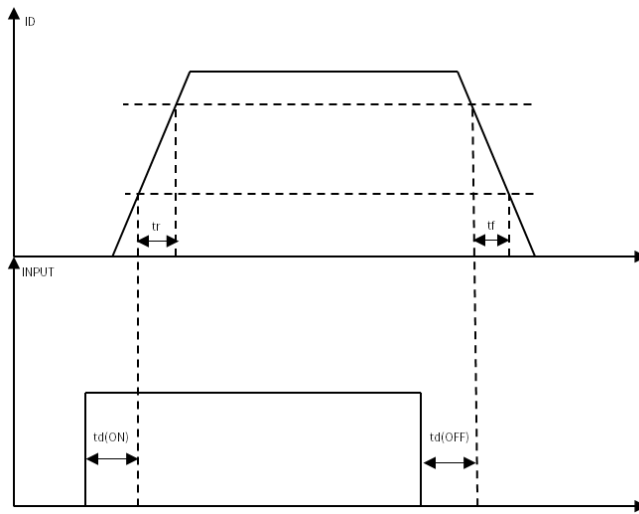


Figure 5-1 Switching characteristics

5.2.2. Electrical characteristics curves

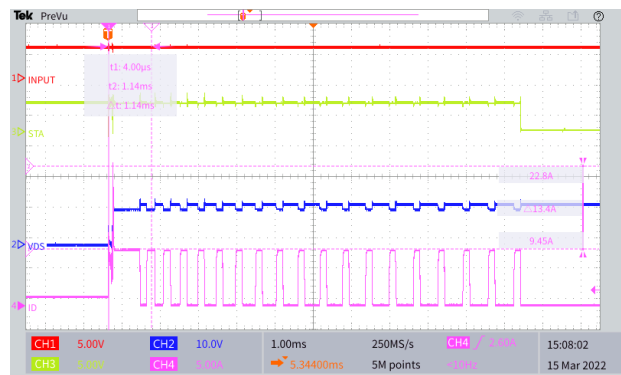
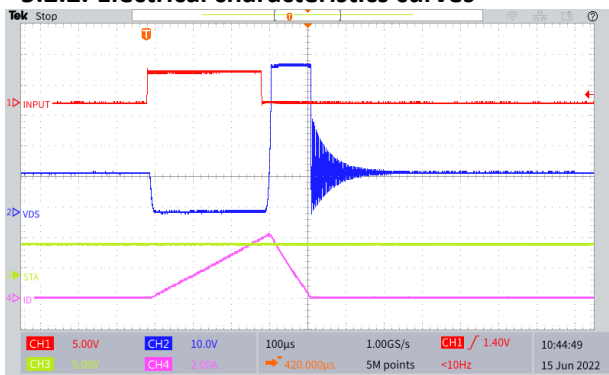




Figure 5-2 Inductive clamp voltage

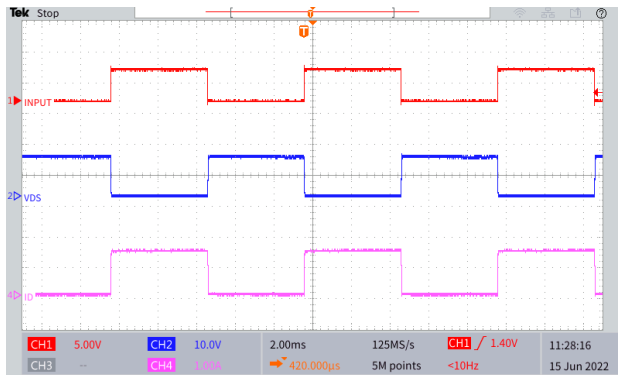


Figure 5-4 Normal load(1.5A, Rload, 25°C)

Figure 5-3 Thermal swing & current limitation

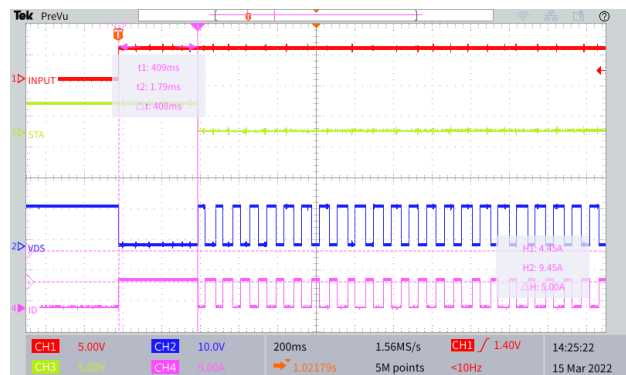


Figure 5-5 Thermal shutdown(5A, Rload, 85°C)

## 6. Protections

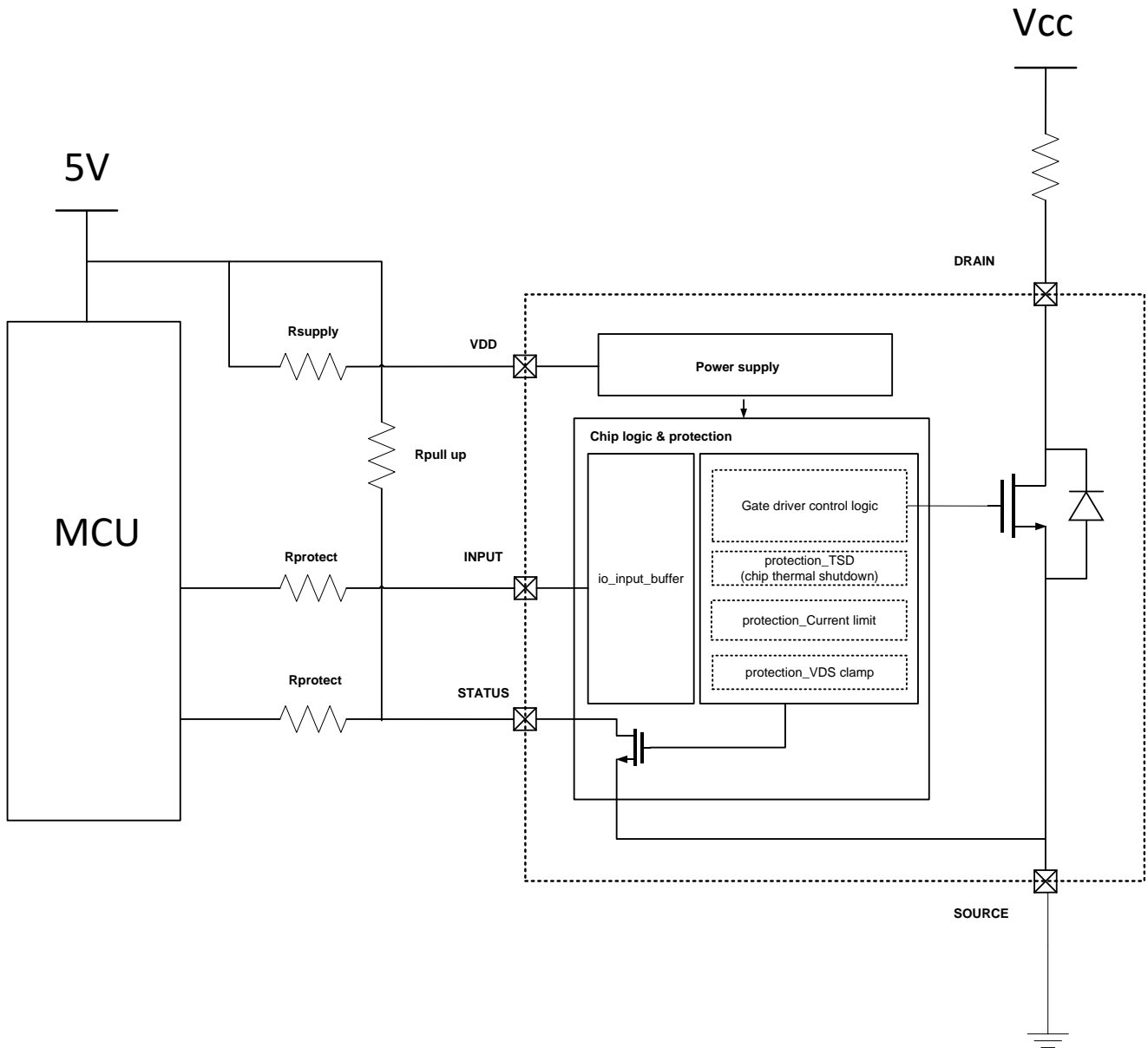
### 6.1. Current limitation

NSE11409-Q1 has current limitation to protect the silicon and bonding wire in case of overload or short circuit to ground.

### 6.2. Thermal shutdown and thermal swing

This device has both absolute and dynamic temperature protection. There are two thermal sensors on the controller and the MOSFET, the one on the MOSFET is the hottest and the one on the controller is the coldest. The absolute temperature protection is to shutdown the MOSFET when the hottest junction temperature exceeds the  $T_{TSD}$ , and the dynamic temperature protection is also to shutdown the MOSFET when the temperature difference between the hottest and the coldest exceeds  $\Delta T_j$ .

## 7. Application Information



### 7.1. MCU I/O protection

NSE11409-Q1 has Zener diodes inside for ESD protection and the intrinsic NPN parasitic bipolar, so that resistors for protection are necessary in series with the digital inputs to limit the current to protect MCU I/Os during transient and reverse battery conditions.

The value of resistors for protection can be calculated by the formula as shown below:

$$\frac{V_{ICL}}{I_{latchup}} \leq R_{prot} \leq \frac{V_{MCU\_OUT} - V_{IH}}{I_{IH\ max}}$$

Where  $V_{ICL}$  is reverse clamp voltage of NSE11409-Q1,  $I_{latchup}$  is the MCU I/O latch up current,  $V_{MCU\_OUT}$  is the output voltage of MCU I/O,  $V_{IH}$  is the High-level input voltage of NSE11409-Q1,  $I_{IH}$  is the high level input current.

Let:

$I_{latchup} \geq 20\text{mA}$ ;  $V_{MCU\_OUT} \geq 4.5\text{V}$ , so  $35\Omega \leq R_{prot} \leq 100\text{k}\Omega$ . The recommended value is  $1\text{k}\Omega$ . The supply resistor is the same.

### 7.2. The value of STATUS pull-up resistor

Because the STATUS pin is open drain output, a pull up resistor is needed to fix the high voltage during normal operation. When the fault occurs, the voltage level of STATUS is pulled down by the internal MOSFET on. The value of pull-up resistor can be calculated by the formula as shown below:

$$\left(\frac{V_{pull-up}}{V_{OL}} - 1\right) \cdot R_{on} < R_{pull-up} < \frac{V_{pull-up} - V_{OH}}{I_{leak}}$$

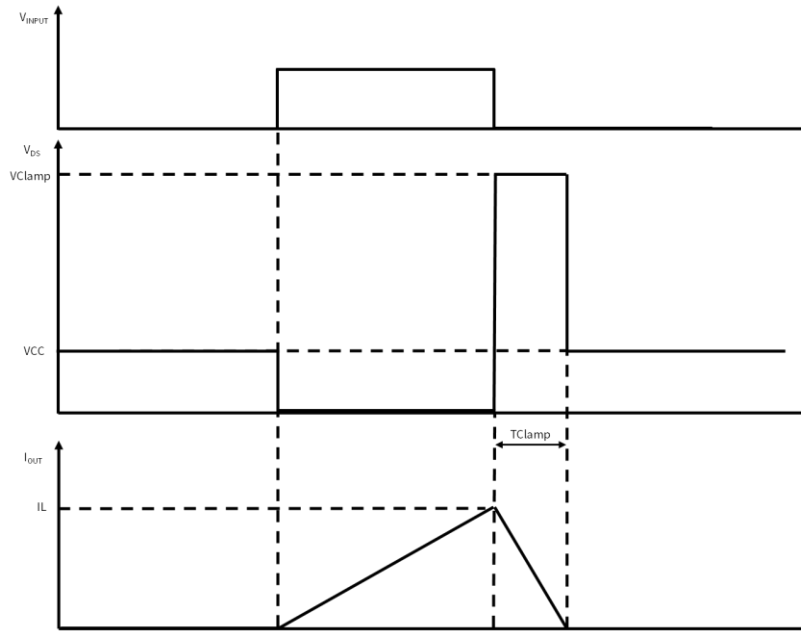
Where  $V_{pull-up}$  is the minimum of pull-up supply,  $V_{OL}$  is the maximum of MCU logic low,  $R_{on}$  is the on resistance of the MOSFET of STATUS pin,  $V_{OH}$  is the minimum of MCU logic high,  $I_{leak}$  is the maximum leakage current of STATUS pin.

Let:

$V_{pullup} = 4.5V$ ;  $R_{on} = V_{STAT}/I_{STAT} = 500\Omega$ ;  $V_{OL} = 0.9V$ ;  $V_{OH} = 2.1V$ ;  $I_{leak} = 10\mu A$ , so  $2k\Omega \leq R_{pull-up} \leq 240k\Omega$ .

### 7.3. Inductive clamp

When the LSS is turned off while driving the inductive load, due to the energy stored on the inductor during the ON time, this energy needs to be dissipated through LSS without an external freewheeling diode. At this point, the inductor will pull the output voltage to a negative voltage. In order to prevent the drain and source terminals of the MOS from exceeding the breakdown voltage of MOS due to excessive voltage, VDS clamps are needed to protect the MOS.



The formula for calculating clamping energy is derived as follows, assuming that the inductance value is  $L$ , low side switch open for a period of time, the current on  $L$  rises to  $I_L$  (less than inductance Saturation current), the energy stored on the inductor is:

$$E_L = \frac{1}{2} \cdot L \cdot I_L^2$$

$$V_{clamp} - V_{CC} = -L \frac{di}{dt}$$

$$di = -\frac{V_{clamp} - V_{CC}}{L} dt$$

$$i = I_L - \left(\frac{V_{clamp} - V_{CC}}{L}\right)t$$

$$E = \int_0^{t_{clamp}} i \times V_{clamp} dt = \int_0^{t_{clamp}} \left( I_L - \left( \frac{V_{clamp} - V_{CC}}{L} \right) t \right) \times V_{clamp} dt = [I_L \times V_{clamp} \times t - \frac{1}{2} \left( \frac{V_{clamp} - V_{CC}}{L} \right) \times V_{clamp} \times t^2]_0^{t_{clamp}}$$

Where,

$$t_{clamp} = \frac{L \times I_L}{V_{clamp} - V_{CC}}$$

So that:

$$E = \frac{1}{2} \cdot I_L^2 \cdot L \cdot \frac{V_{clamp}}{V_{clamp} - V_{CC}}$$

For better working reliability, a diode (e.g. 40V, 1A or 2A) could be placed in reverse parallel with the inductor according to the actual load current. Figure 7-1 shows the recommended application circuit for inductive loads of NSE11409.

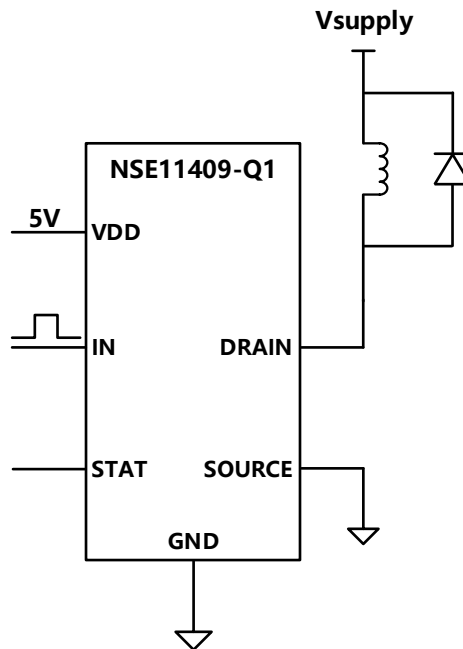
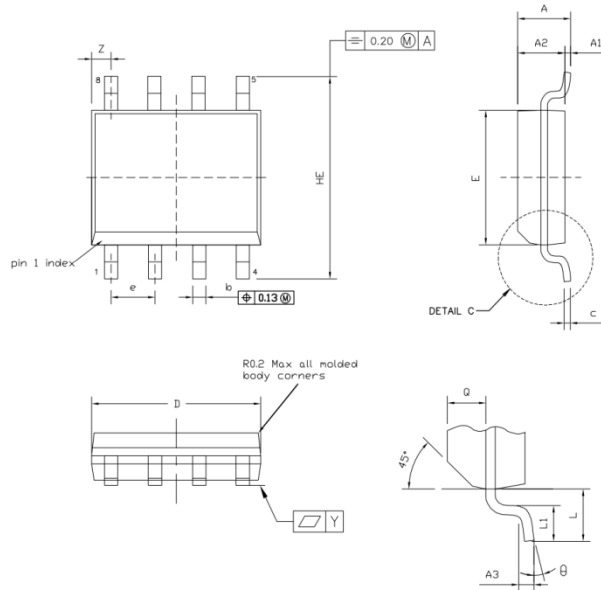


Figure 7-1 Recommended application circuit for inductive loads of NSE11409

### 8. Package Information

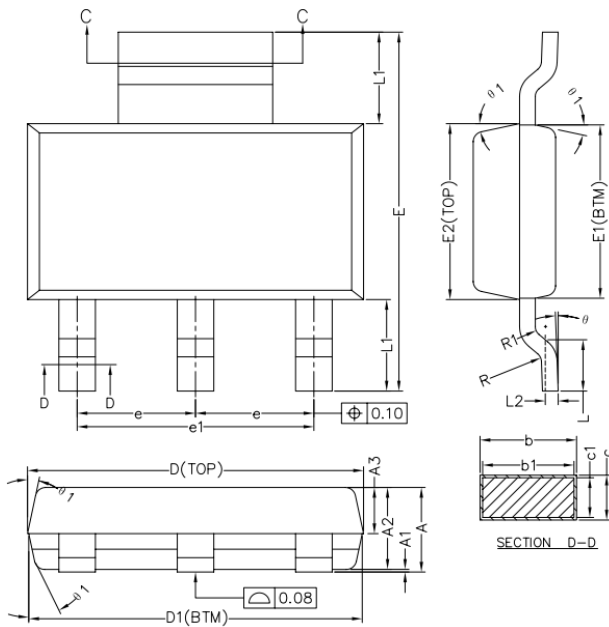
#### 8.1. SOP8



\* CONTROLLING DIMENSION : MM

SYMBOL	MILLIMETER		
	MIN.	NOM.	MAX.
A	---	---	1.75
A1	0.10	---	0.25
A2	1.25	1.35	1.45
b	0.33	0.38	0.49
c	0.19	0.20	0.25
D	4.80	4.90	5.00
E	3.80	3.90	4.00
Q	0.60	0.65	0.70
HE	5.80	6.00	6.20
e	1.27 BSC		
L	1.05 BSC		
L1	0.40	0.64	1.00
Y	---	0.10	---
Z	0.3	0.5	0.7
A3	0.25 BSC		
θ	0°	5°	8°

#### 8.2. SOT223



COMMON DIMENSIONS  
(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX
A	—	—	1.80
A1	0.02	—	0.10
A2	1.50	1.60	1.70
A3	0.80	0.90	1.00
b	0.67	—	0.80
b1	0.66	0.71	0.76
b2	2.96	—	3.09
b3	2.95	3.00	3.05
c	0.30	—	0.35
c1	0.29	0.30	0.31
D	6.48	6.53	6.58
D1	6.43	6.48	6.53
E	6.80	—	7.20
E1	3.30	3.38	3.48
E2	3.33	3.43	3.53
e	2.25	2.30	2.35
e1	4.50	4.60	4.70
L	0.80	1.00	1.20
L1	1.78REF		
L2	0.25BSC		
R	0.10	—	—
R1	0.10	—	—
θ	0°	—	8°
θ 1	10°	12°	14°

NOTES:  
ALL DIMENSIONS REFER TO JEDEC STANDARD TO261-AA  
DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS,  
BODY LENGTH INCLUDING MOLD PROTRUSIONS SHALL NOT EXCEED 6.7mm.

**9. Order Information**

<i>Part Number</i>	<i>Package</i>	<i>MSL</i>	<i>Temperature</i>	<i>SPQ</i>
NSE11409-QSPR	SOP8	3	-40 to 125°C	2500
NSE11409-QSTBR	SOT223	3	-40 to 125°C	2500
NOTE: All packages are RoHS-compliant				

**10. Revision history**

<b>Revision</b>	<b>Description</b>	<b>Date</b>
1V0	Initial version	2022/12
1V1	Add thermal information & Switching characteristics & Inductive clamp	2023/07